Search Notes



Application/Control No.	Applicant(s
	Reexamina

10/815,239 Examiner

Shin-Hon Chen

Applicant(s)/Patent under Reexamination

AHUJA ET AL.

Art Unit

2131

SEARCHED				
Class	Subclass	Date	Examiner	
709	224,249	6/8/2007	S.C.	
713	182,162	6/8/2007	S.C.	
713	151	6/8/2007	S.C.	
726	3,11,13	6/8/2007	S.C.	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	6/8/2007	S.C.
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